## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10571862	IP, CHARLOTTE
Examiner	Art Unit
Young J Kim	1637

SEARCHED						
Class	Subclass	Date	Examiner			

SEARCH NOTES				
Search Notes	Date	Examiner		
searched patent databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	2/15/2008	YJK		
see enclosed for text-search strategy	2/15/2008	YJK		
STIC assisted search of SEQ ID Numbers 1-4; (commercial, patent, and published databases)	2/15/2008	YJK		

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	

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